### **VE320 – Summer 2021**

### **Introduction to Semiconductor Devices**

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Chapter 8 The pn Junction Diode

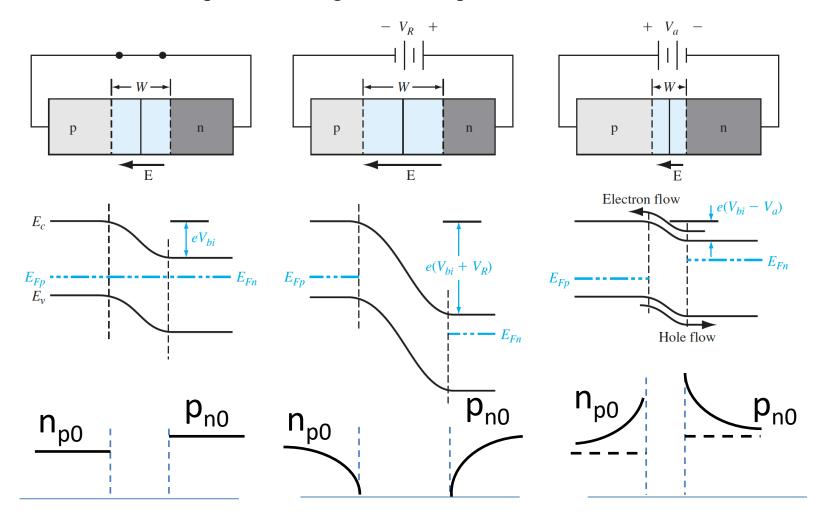
### Outline

### 8.1 pn junction current

- 8.2 Generation-recombination currents
- 8.3 High-injection levels
- 8.4 A few more points on pn junctions (not in the textbook)



### Qualitative Description of Charge Flow in a pn Junction

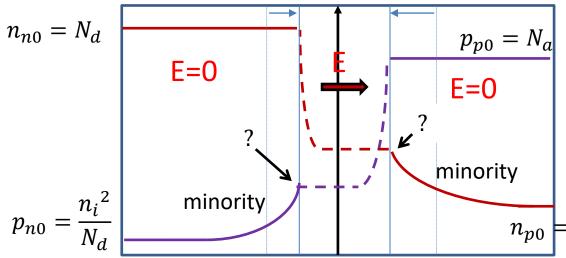


Goal: to find the analytical expression of current

$$\frac{\partial n}{\partial t} = D_n \frac{\partial^2 n}{\partial x^2} + \mu_n E \frac{\partial n}{\partial x} + n \mu_n \frac{\partial E}{\partial x} - \frac{\Delta n}{\tau} + G_{ex}$$

$$\frac{\partial p}{\partial t} = D_p \frac{\partial^2 p}{\partial x^2} - \mu_p E \frac{\partial p}{\partial x} - p \mu_p \frac{\partial E}{\partial x} - \frac{\Delta p}{\tau} + G_{ex}$$

holes as minority



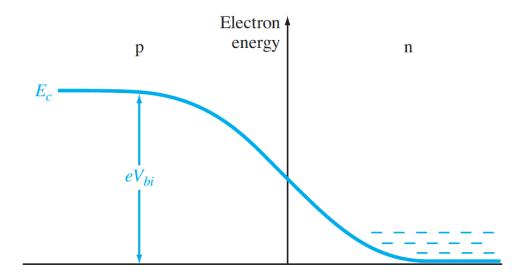
Electrons as minority

- How to simplify?
- Boundary condition?
- how to get total current from minority currents?

$$=\frac{n_i^2}{N_a}$$

#### Assumptions of an ideal PN junction

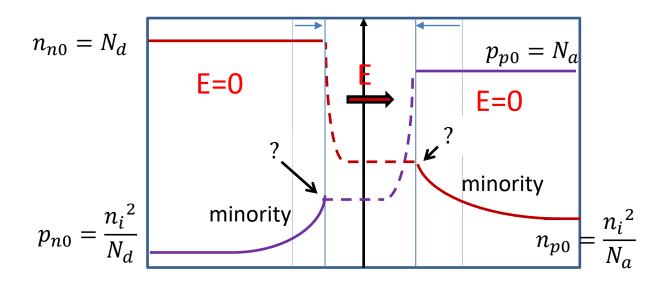
- 1. The abrupt depletion layer approximation applies. The space charge regions have abrupt boundaries, and the semiconductor is neutral outside of the depletion region.
- 2. The Maxwell–Boltzmann approximation applies to carrier statistics.
- 3. The concepts of low injection and complete ionization apply.
- **4a.** The total current is a constant throughout the entire pn structure.
- **4b.** The individual electron and hole currents are continuous functions through the pn structure.
- **4c.** The individual electron and hole currents are constant throughout the depletion region.



$$V_{bi} = V_t \ln \left( \frac{N_a N_d}{n_i^2} \right)$$

$$n_{p0} = n_{n0} \exp\left(\frac{-eV_{bi}}{kT}\right)$$

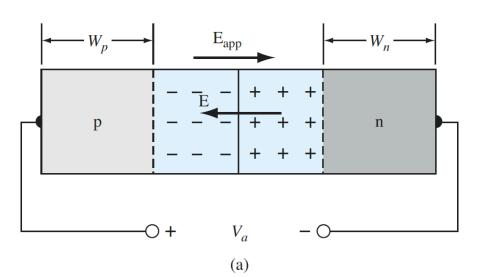
$$p_{n0} = p_{p0} exp\left(\frac{-eV_{bi}}{kT}\right) \qquad n_{p0} = n_{n0} \exp\left(\frac{-eV_{bi}}{kT}\right)$$

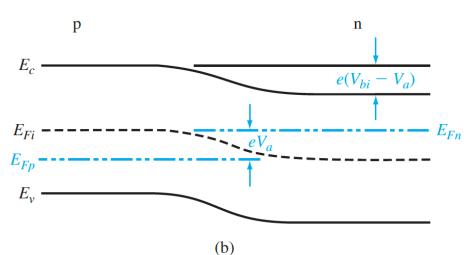


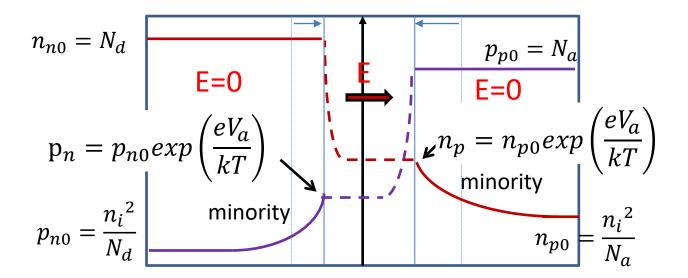
$$p_{n0} = p_{p0} exp\left(\frac{-eV_{bi}}{kT}\right) \qquad n_{p0} = n_{n0} \exp\left(\frac{-eV_{bi}}{kT}\right)$$

$$\downarrow \qquad \qquad \downarrow$$

$$p_n = p_{p0} exp\left(\frac{-e(V_{bi} - V_a)}{kT}\right) = p_{n0} exp\left(\frac{eV_a}{kT}\right) \qquad n_p = n_{p0} exp\left(\frac{eV_a}{kT}\right)$$



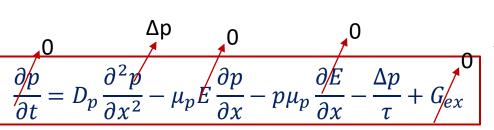




#### Problem Example

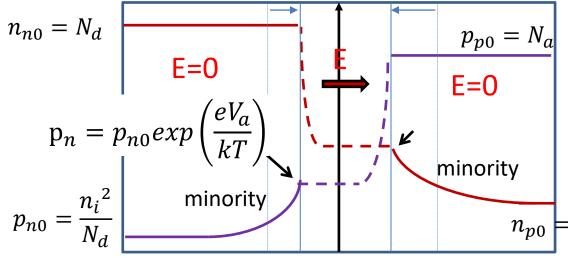
Consider a silicon pn junction at T = 300K. Assume the doping concentration in the n region is  $N_d = 10^{16}$  cm<sup>-3</sup> and the doping concentration in the p region is  $N_a = 6 \times 10^{15}$  cm<sup>-3</sup>. Assume a forward bias of 0.6V is applied to the pn junction. Calculate the minority concentration at the edge of the depletion region.

#### Minority carrier distribution



$$D_p \frac{\partial^2 \Delta p}{\partial x^2} - \frac{\Delta p}{\tau} = 0$$

holes as minority



- How to simplify?
- Boundary condition?
- how to get total current from minority currents?

$$\frac{n_i^2}{N_a}$$

$$\delta p_n(x) = p_n(x) - p_{n0} = Ae^{x/L_p} + Be^{-x/L_p} \quad (x \le -x_p)$$

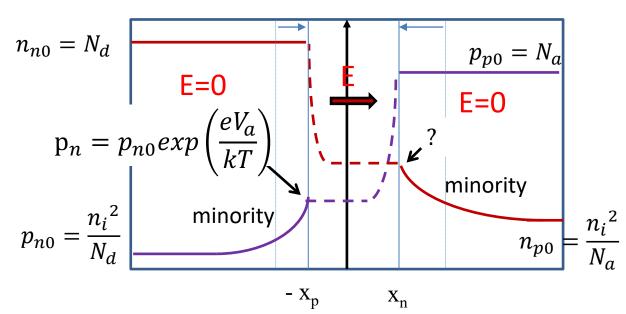
$$\delta n_p(x) = n_p(x) - n_{p0} = Ce^{x/L_n} + De^{-x/L_n} \quad (x \ge x_n)$$

$$p_n(x_n) = p_{n0} \exp\left(\frac{eV_a}{kT}\right)$$

$$n_p(-x_p) = n_{p0} \exp\left(\frac{eV_a}{kT}\right)$$

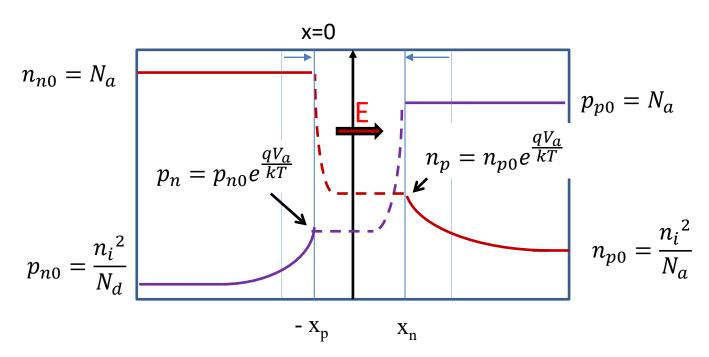
$$p_n(x \to +\infty) = p_{n0}$$

$$n_p(x \to -\infty) = n_{p0}$$



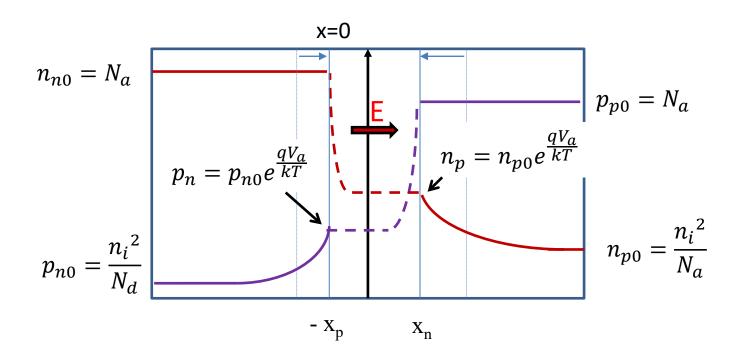
$$\Rightarrow \Delta p = p_n(x) - p_{n0} = p_{n0} (e^{\frac{qV_a}{kT}} - 1)e^{(x + x_p)/L_p}$$

$$\Rightarrow \Delta n = n_p(x) - n_{p0} = n_{p0} (e^{\frac{qV_a}{kT}} - 1)e^{(x_n - x)/L_n}$$



$$p = p_o + \delta p = n_i \exp\left(\frac{E_{Fi} - E_{Fp}}{kT}\right)$$

$$n = n_o + \delta n = n_i \exp\left(\frac{E_{Fn} - E_{Fi}}{kT}\right)$$



$$p = p_o + \delta p = n_i \exp\left(\frac{E_{Fi} - E_{Fp}}{kT}\right) \qquad n = n_o + \delta n = n_i \exp\left(\frac{E_{Fn} - E_{Fi}}{kT}\right)$$

$$np = n_i^2 \exp\left(\frac{E_{Fn} - E_{Fp}}{kT}\right)$$

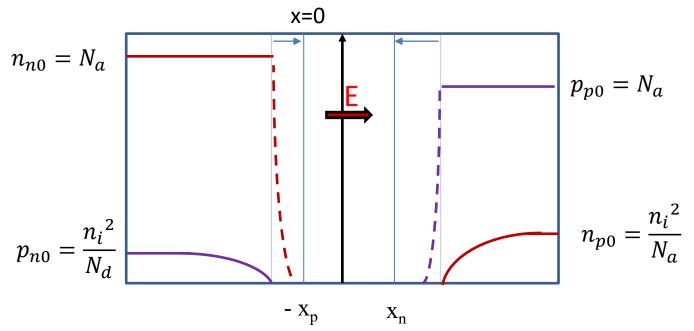
$$E_c$$

$$E_{Fi}$$

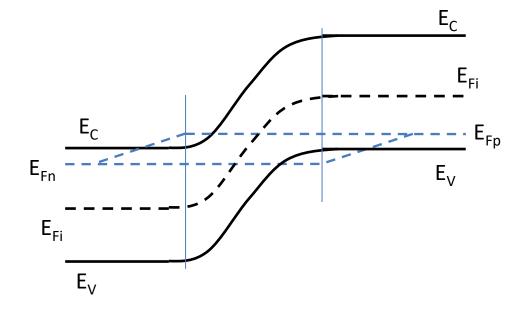
$$E_{Fi}$$

$$E_{V}$$

$$p = p_o + \delta p = n_i \exp\left(\frac{E_{Fi} - E_{Fp}}{kT}\right) \qquad n = n_o + \delta n = n_i \exp\left(\frac{E_{Fn} - E_{Fi}}{kT}\right)$$
$$np = n_i^2 \exp\left(\frac{E_{Fn} - E_{Fp}}{kT}\right)$$



$$p = p_o + \delta p = n_i \exp\left(\frac{E_{Fi} - E_{Fp}}{kT}\right) \qquad n = n_o + \delta n = n_i \exp\left(\frac{E_{Fn} - E_{Fi}}{kT}\right)$$
$$np = n_i^2 \exp\left(\frac{E_{Fn} - E_{Fp}}{kT}\right)$$



charge carrier transport: <u>forward bias</u>

$$J_{n,diff} = qD_n \frac{dn_p}{dx} = -\frac{qD_n n_{p0}}{L_n} (e^{\frac{qV_a}{kT}} - 1)e^{\frac{x_n - x}{L_n}}$$

$$I_{p,diff} = -qD_{p} \frac{dp_{n}}{dx} = -\frac{qD_{p}p_{n0}}{L_{p}} (e^{\frac{qV_{a}}{kT}} - 1)e^{\frac{x+x_{p}}{L_{p}}}$$

$$n_{n0} = N_{d}$$

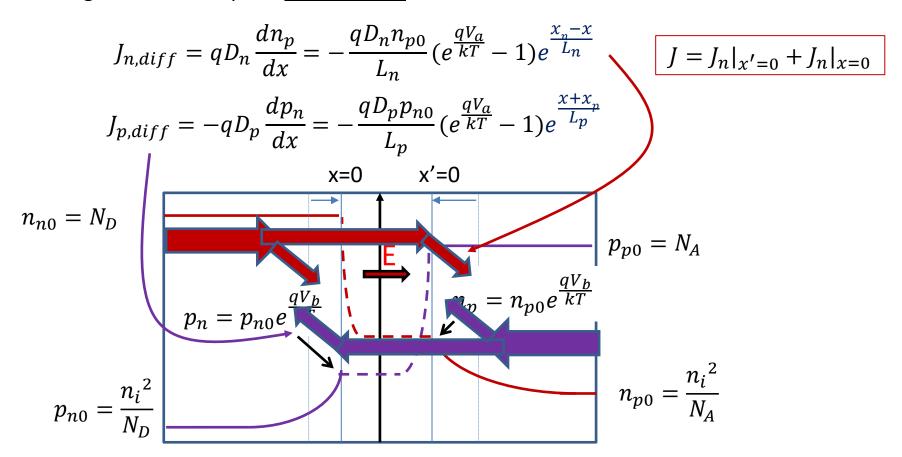
$$p_{n} = p_{n0}e^{\frac{qV_{a}}{kT}}$$

$$p_{n0} = \frac{n_{i}^{2}}{N_{d}}$$

$$n_{p0} = \frac{n_{i}^{2}}{N_{a}}$$

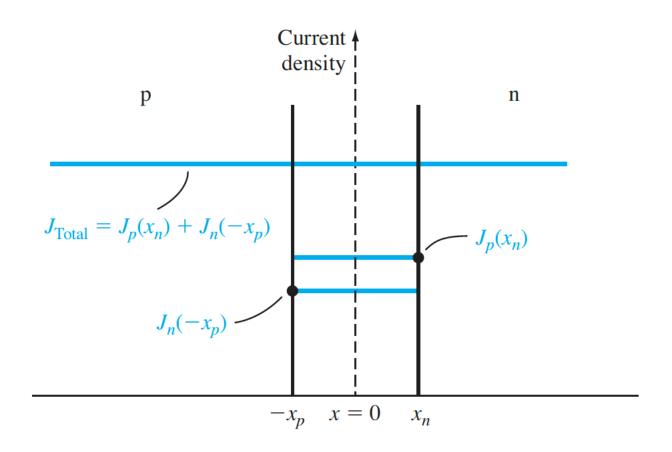
$$n_{p0} = \frac{n_{i}^{2}}{N_{a}}$$

charge carrier transport: <u>forward bias</u>



Assumption: No recombination-generation in depletion region.

Ideal pn junction current



Assumption: No recombination-generation in depletion region.

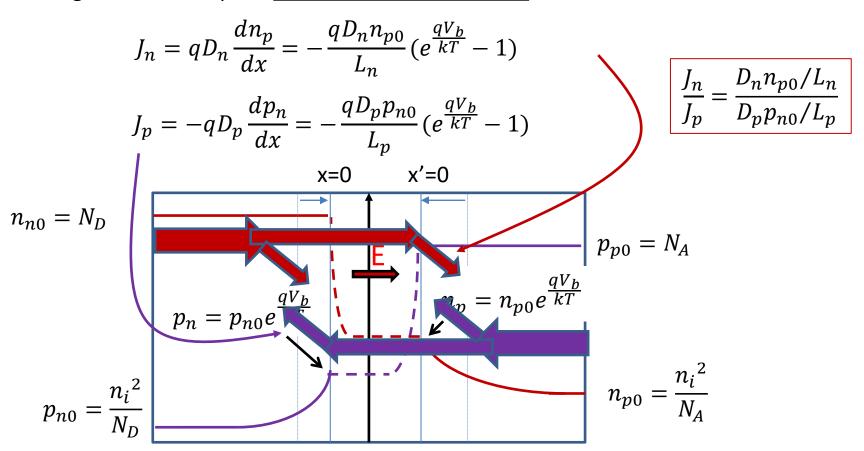
• Ideal pn junction current

$$J = J_n|_{x'=0} + J_n|_{x=0}$$

$$J = J_s(e^{\frac{qV_b}{kT}} - 1)$$

$$J_s = \frac{qD_n n_{p0}}{L_n} + \frac{qD_p p_{n0}}{L_p}$$

charge carrier transport: <u>forward bias: current ratio</u>



Assumption: No recombination-generation in depletion region.



charge carrier transport: reverse bias

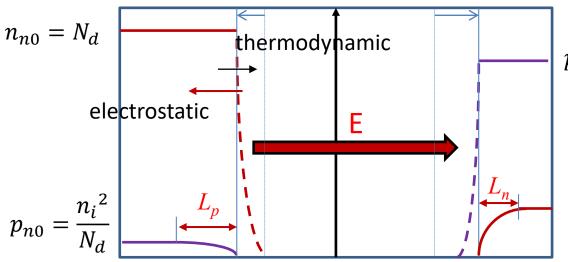
$$J_n = qD_n \frac{dn_p}{dx} = \frac{qD_n n_{p0}}{L_n}$$

$$J_p = -qD_p \frac{dp_n}{dx} = \frac{qD_p p_{n0}}{L_p}$$

$$J = J_n|_{x'=0} + J_n|_{x=0}$$

$$J = J_S \left( e^{\frac{qV_b}{kT}} - 1 \right) = -J_S$$

$$J_s = \frac{qD_n n_{p0}}{L_n} + \frac{qD_p p_{n0}}{L_p}$$

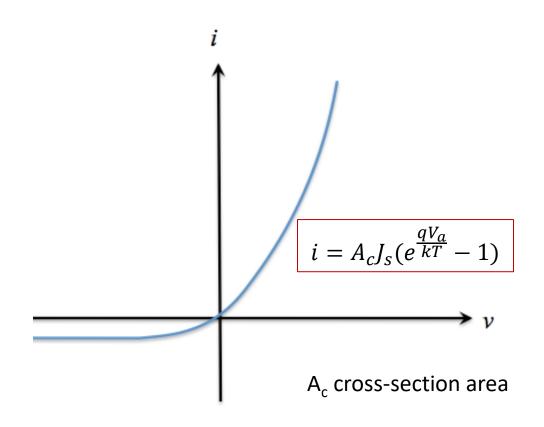


$$p_{p0} = N_a$$

$$n_{p0} = \frac{n_i^2}{N_a}$$

Assumption: No recombination-generation in depletion region.

charge carrier transport: <u>forward bias</u>



$$J = J_n|_{x'=0} + J_n|_{x=0}$$

$$J = J_s(e^{\frac{qV_b}{kT}} - 1)$$

$$J_s = \frac{qD_n n_{p0}}{L_n} + \frac{qD_p p_{n0}}{L_p}$$

#### Problem Example #2

Given the following parameters in a silicon pn junction, determine the ideal reverse-saturation current density of this pn junction at 300K.

$$N_a = N_d = 10^{16} \text{ cm}^{-3}$$
  $n_i = 1.5 \times 10^{10} \text{ cm}^{-3}$   $D_n = 25 \text{ cm}^2/\text{s}$   $\tau_{p0} = \tau_{n0} = 5 \times 10^{-7} \text{ s}$   $\tau_{p0} = 10 \text{ cm}^2/\text{s}$   $\epsilon_r = 11.7$ 

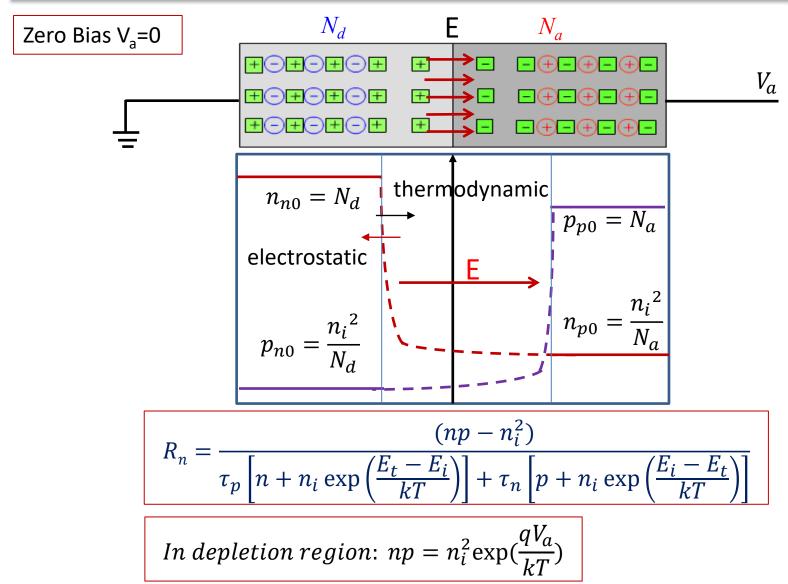
## Outline

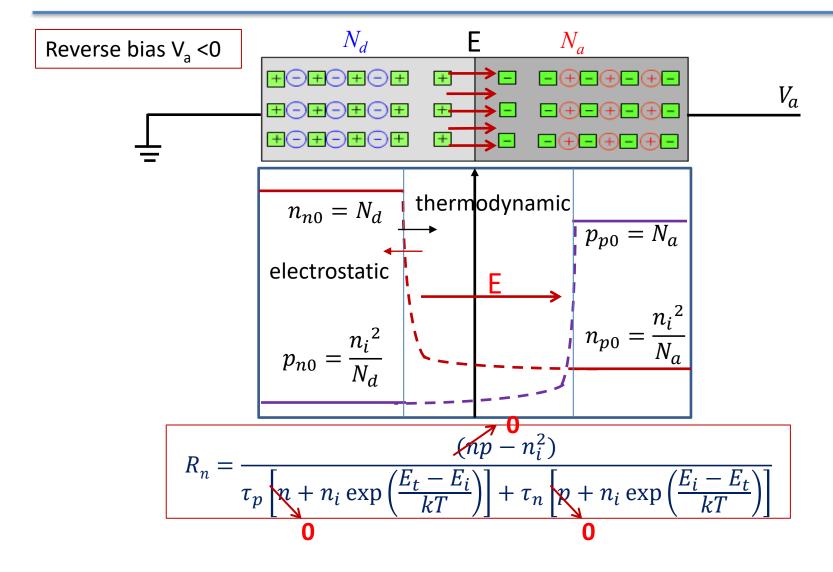
8.1 pn junction current

#### 8.2 Generation-recombination currents

8.3 High-injection levels

8.4 A few more points on pn junctions (not in the textbook)





Reverse bias V<sub>a</sub> <0

To simplify the calculation, we assume

$$E_t = E_i$$
,  $\tau_n = \tau_p = \tau$ 

$$R_n = \frac{-n_i}{2\tau} = -G_0$$

$$R_{n} = \frac{(np - n_{i}^{2})}{\tau_{p} \left[ n + n_{i} \exp\left(\frac{E_{t} - E_{i}}{kT}\right) \right] + \tau_{n} \left[ p + n_{i} \exp\left(\frac{E_{i} - E_{t}}{kT}\right) \right]}$$

Reverse bias V<sub>a</sub> <0

To simplify the calculation, we assume

$$E_t = E_i$$
,  $\tau_n = \tau_p = \tau$ 

$$R_n = \frac{-n_i}{2\tau} = -G_0$$

Current density from G-R in the depletion region:

$$J_r = \int_0^W qG_0 dx = \frac{qWn_i}{2\tau}$$

$$R_n = \frac{(np - n_i^2)}{\tau_p \left[ n + n_i \exp\left(\frac{E_t - E_i}{kT}\right) \right] + \tau_n \left[ p + n_i \exp\left(\frac{E_i - E_t}{kT}\right) \right]}$$

Reverse bias V<sub>a</sub> <0

To simplify the calculation, we assume

$$E_t = E_i$$
,  $\tau_n = \tau_p = \tau$ 

$$R_n = \frac{-n_i}{2\tau} = -G_0$$

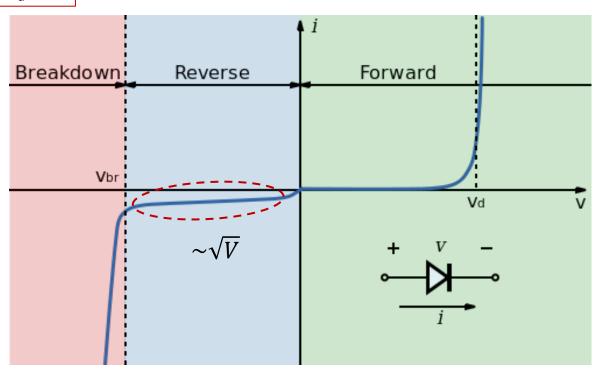
Current density from G-R in the depletion region:

$$J_r = \int_0^W qG_0 dx = \frac{qWn_i}{2\tau}$$

$$W = a + b = \sqrt{\frac{2\varepsilon(V_{bi} - V_a)}{q} \frac{N_d + N_a}{N_a N_d}}$$

$$R_{n} = \frac{(np - n_{i}^{2})}{\tau_{p} \left[ n + n_{i} \exp\left(\frac{E_{t} - E_{i}}{kT}\right) \right] + \tau_{n} \left[ p + n_{i} \exp\left(\frac{E_{i} - E_{t}}{kT}\right) \right]}$$

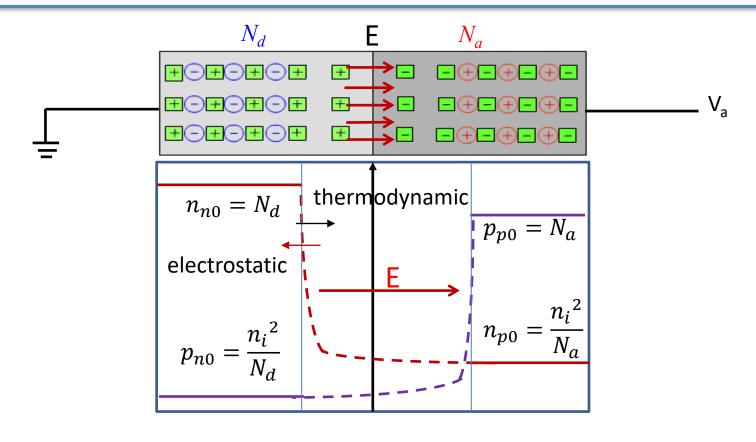
Reverse bias V<sub>a</sub> <0



Current density from G-R in the depletion region:

$$J_r = \int_0^W qGdx = \frac{qWn_i}{2\tau}$$

$$W = a + b = \sqrt{\frac{2\varepsilon(V_{bi} - V_a)}{q} \frac{N_d + N_a}{N_a N_d}}$$



In depletion region:  $np = n_i^2 \exp(\frac{qV_a}{kT})$ 

To simplify the calculation, we assume

$$E_t = E_i$$
,  $\tau_n = \tau_p = \tau$ 

$$R_n = \frac{np - n_i^2}{\tau(n + p + 2n_i)}$$

When n=p, U reaches its max value.

$$R_{n,max} = \frac{np - n_i^2}{\tau \left[ n_i \exp(\frac{qV_a}{2kT}) + n_i \exp(\frac{qV_a}{2kT}) + 2n_i \right]} = \frac{n_i \left[ \exp\left(\frac{qV_a}{kT}\right) - 1 \right]}{2\tau \left[ \exp\left(\frac{qV_a}{2kT}\right) + 1 \right]}$$

$$= \frac{n_i \left[ \exp \left( \frac{qV_a}{2kT} \right) - 1 \right]}{2\tau}$$

In depletion region: 
$$np = n_i^2 \exp(\frac{qV_a}{kT})$$

$$R_{n,max} = \frac{n_i}{2\tau} \left[ \exp\left(\frac{qV_a}{2kT}\right) - 1 \right]$$

Current density from G-R in the depletion region:

$$J_r = \int_0^W q R_{n,max} dx = \frac{qW n_i}{2\tau} \left[ \exp\left(\frac{qV_a}{2kT}\right) - 1 \right]$$

For a non-ideal pn junction, the total current density:

$$J = J_F + J_r = J_S \left[ \exp\left(\frac{qV_a}{kT}\right) - 1 \right] + \frac{qWn_i}{2\tau} \left[ \exp\left(\frac{qV_a}{2kT}\right) - 1 \right]$$

$$J = J_F + J_r = J_S \left[ \exp\left(\frac{qV_a}{kT}\right) - 1 \right] + \frac{qWn_i}{2\tau} \left[ \exp\left(\frac{qV_a}{2kT}\right) - 1 \right]$$

Forward bias V > 3kT/q = 0.078V:

$$J = J_F + J_r = J_S \exp\left(\frac{qV_a}{kT}\right) + \frac{qWn_i}{2\tau} \exp\left(\frac{qV_a}{2kT}\right) = J_0 \exp\left(\frac{qV_a}{nkT}\right)$$
 the ideality factor

$$J = J_F + J_r = J_s \left[ \exp\left(\frac{qV_a}{kT}\right) - 1 \right] + \frac{qWn_i}{2\tau} \left[ \exp\left(\frac{qV_a}{2kT}\right) - 1 \right]$$

Forward bias V> 3kT/q=0.078V:

$$J = J_F + J_r = J_S \exp\left(\frac{qV_a}{kT}\right) + \frac{qWn_i}{2\tau} \exp\left(\frac{qV_a}{2kT}\right) = J_0 \exp\left(\frac{qV_a}{nkT}\right)$$
 the ideality factor

Reverse bias:

$$J_0 = -J_S - \frac{qWn_i}{2\tau} = -\left(\frac{qD_nn_{p0}}{L_n} + \frac{qD_pp_{n0}}{L_p}\right) - \frac{qWn_i}{2\tau}$$

## Outline

- 8.1 pn junction current
- 8.2 Generation-recombination currents

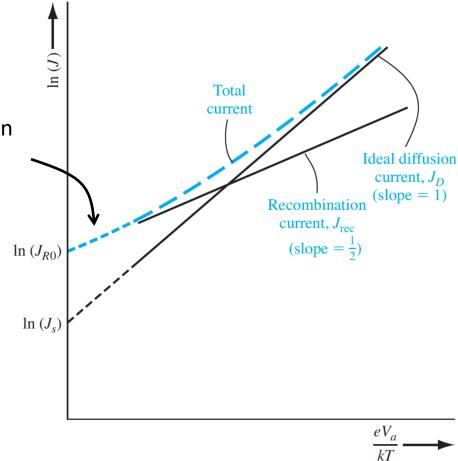
### 8.3 High-injection levels

8.4 A few more points on pn junctions (not in the textbook)

# 8.3 High inject level

$$J = J_F + J_r = J_S \exp\left(\frac{qV_a}{kT}\right) + \frac{qWn_i}{2\tau} \exp\left(\frac{qV_a}{2kT}\right) = J_0 \exp\left(\frac{qV_a}{nkT}\right)$$

e-h pairs recombine in the depletion region







## 8.3 High inject level

$$J = J_F + J_T = J_S \exp\left(\frac{qV_a}{kT}\right) + \frac{qWn_i}{2\tau} \exp\left(\frac{qV_a}{2kT}\right) = J_0 \exp\left(\frac{qV_a}{nkT}\right)$$
Resistivity limited

Recombination

Recombination

Relation

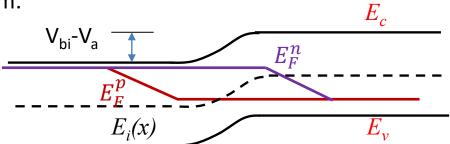




## Outline

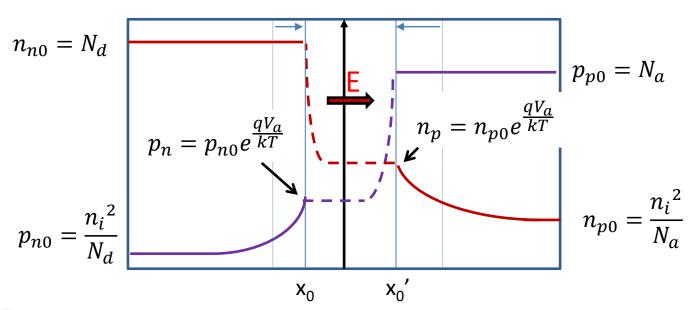
- 8.1 pn junction current
- 8.2 Generation-recombination currents
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Energy diagram:



Forward bias

To understand this, see the next page.







Current and Fermi level

$$J_{n} = J_{diff,n} + J_{drift,n}$$

$$J_{n} = qD_{n}\frac{dn}{dx} + nq\mu_{n}|E|$$

$$= kT\mu_{n}\frac{dn}{dx} + nq\mu_{n}|E|$$

$$= nq\mu_{n}\left(\frac{kT}{nq}\frac{dn}{dx} + |E|\right)$$

$$= nq\mu_{n}\left[\frac{kT}{q}\frac{d\ln(n)}{dx} + |E|\right]$$

$$= nq\mu_{n}\left[\frac{dE_{F}}{qdx} - \frac{dE_{i}}{qdx} + |E|\right]$$

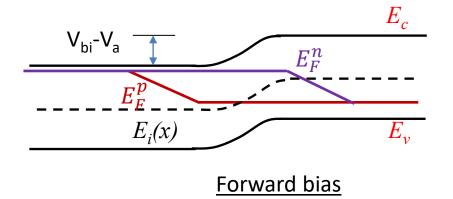
$$\Rightarrow \frac{d}{dx}\ln(n) = \frac{d}{dx}\left(\frac{E_{F} - E_{i}}{kT}\right) \Rightarrow \ln(n) = \ln(n_{i}) + \frac{E_{F} - E_{i}}{kT}$$

$$= nq\mu_{n}\left[\frac{dE_{F}}{qdx} - \frac{dE_{i}}{qdx} + |E|\right]$$

$$\Rightarrow \frac{d}{dx}\ln(n) = \frac{d}{dx}\left(\frac{E_{F} - E_{i}}{kT}\right) = \frac{1}{kT}\left(\frac{dE_{F}}{dx} - \frac{dE_{i}}{dx}\right)$$

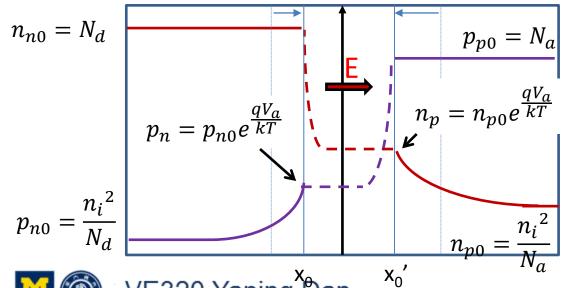
$$\therefore \frac{dE_{i}}{dx} = -q\frac{dV(x)}{dx} = |E|$$

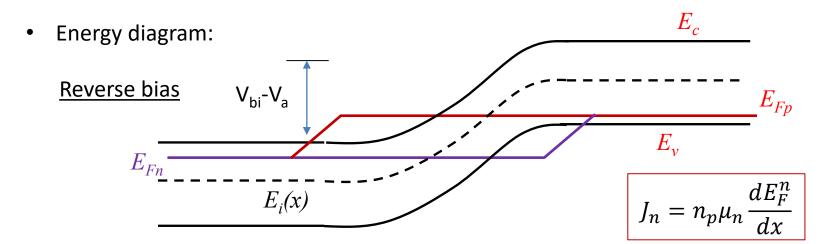
#### Energy diagram:

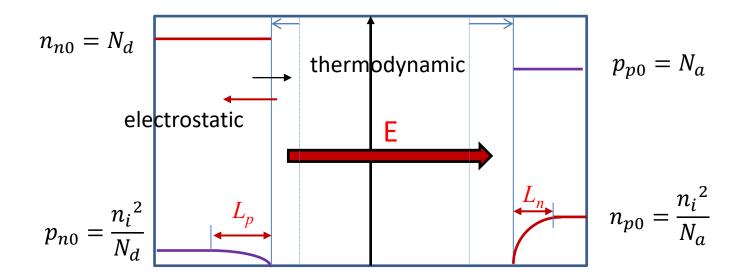


$$J_n = n_{p0} + \Delta n \approx \Delta n$$

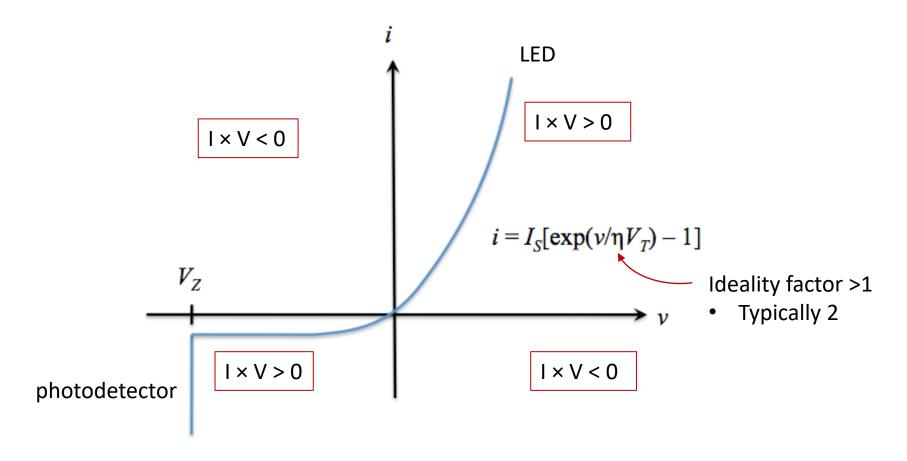
$$J_n = n_p \mu_n \frac{dE_F^n}{dx}$$







• Energy consumption:



Energy consumption:

